SCLS340A - MARCH 1996 - REVISED MAY 1997

- Compare Two 8-Bit Words
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These magnitude comparators perform comparisons of two 8-bit binary or BCD words. These devices provide $\overline{P} = \overline{Q}$ and $\overline{P} > \overline{Q}$ outputs.

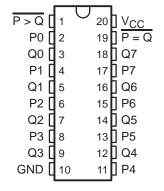
The SN54HC684 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC684 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

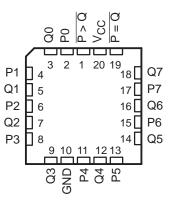
DATA	OUTPUTS						
INPUTS P, Q	P = Q	P > Q					
P = Q	L	Н					
P > Q	Н	L					
P < Q	н	Н					

The \overline{P} < \overline{Q} function can be generated by applying \overline{P} = \overline{Q} and \overline{P} > \overline{Q} to a 2-input NAND gate.

SN54HC684 . . . J OR W PACKAGE SN74HC684 . . . DW OR N PACKAGE (TOP VIEW)



SN54HC684 . . . FK PACKAGE (TOP VIEW)

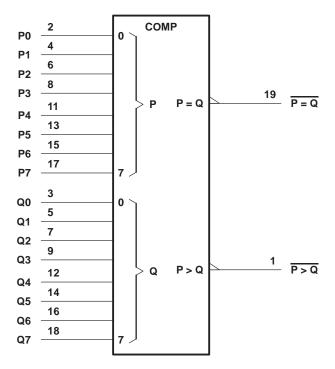




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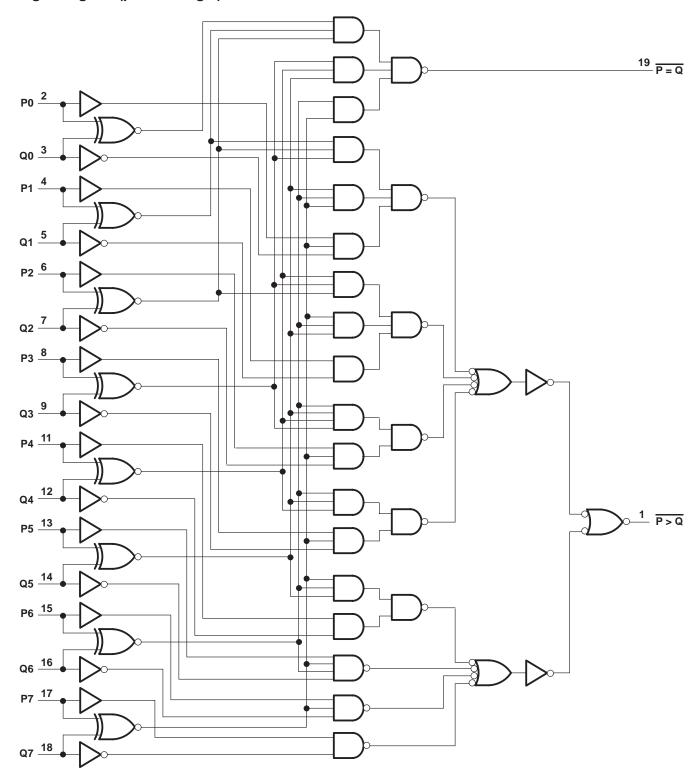


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	–0.5 V to 7 V
Output voltage range, V _O (see Note 1)	0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			SI	SN54HC684		SN74HC684			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC	Supply voltage		2	5	6	2	5	6	V	
VIH High-level input voltage	V _{CC} = 2 V	1.5			1.5					
	V _{CC} = 4.5 V	3.15			3.15			V		
	VCC = 6 V	4.2		7	4.2					
V _{IL} Low-level input voltage	V _{CC} = 2 V	0	Ş	0.5	0		0.5	V		
	V _{CC} = 4.5 V	0	10	1.35	0		1.35			
		VCC = 6 V	0	5	1.8	0		1.8		
٧ _I	Input voltage		0 4	5	VCC	0		VCC	V	
٧o	Output voltage		0)	VCC	0		VCC	V	
t _t Input transition (rise and fall) times	V _{CC} = 2 V	0		1000	0		1000			
	V _{CC} = 4.5 V	0		500	0		500	ns		
	V _{CC} = 6 V	0		400	0		400			
TA	Operating free-air temperature		-55		125	-40		85	°C	

^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T _A = 25°C			SN54HC684		SN74HC684		UNIT	
TAKAWILTER	TEST CONDITIONS		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		$I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -4 mA	4.5 V	3.98	4.30		3.7	N	3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.80		5.2	'In	5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1	6	0.1		0.1	
VOL			6 V		0.001	0.1	<i>7</i> 70	0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26	06	0.4		0.33]
		I _{OL} = 5.2 mA	6 V		0.15	0.26	ď	0.4		0.33	
lін	$V_I = V_{CC}$		6 V		0.1	100		1000		1000	nA
I _{IL}	V _I = 0		6 V		-0.1	-100		-1000		-1000	nA
Icc	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

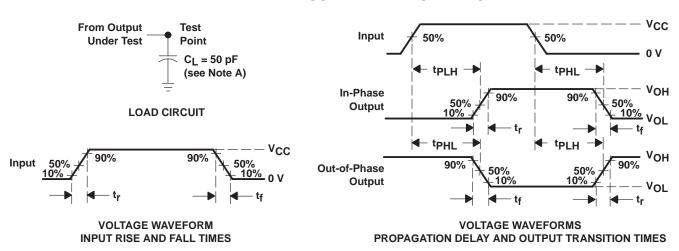
PARAMETER FROM TO	FROM TO ,		Vaa	T,	Վ = 25° C	;	SN54HC684	SN74HC684	UNIT
FARAMETER	(INPUT)	(OUTPUT)	JT) VCC	MIN	TYP	MAX	MIN MAX	MIN MAX	ONIT
		2 V		130	275	413	344		
t _{pd}	P or Q	Any	4.5 V		26	55	4/88	69	ns
		6 V		22	47	70	58		
			2 V		38	75	\$ 110	95	
t _t		Any	4.5 V		8	15	22	19	ns
			6 V		6	13	19	16	

operating characteristics, T_A = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load	40	pF

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns, t_f = 6 ns.
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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